

BLF2425M7L100; BLF2425M7LS100

Power LDMOS transistor

Rev. 1 — 6 December 2013

Product data sheet

1. Product profile

1.1 General description

100 W LDMOS power transistor for industrial applications at frequencies from 2300 MHz to 2400 MHz.

Table 1. Typical performance

Typical RF performance at $T_{case} = 25\text{ °C}$ in a common source class-AB production test circuit.

Test signal	f (MHz)	I_{Dq} (mA)	V_{DS} (V)	$P_{L(AV)}$ (W)	G_p (dB)	η_D (%)	ACPR _{885k} (dBc)	ACPR _{5M} (dBc)
IS-95	2300 to 2400	900	28	20	18	27	-46 ^[1]	-
1 carrier W-CDMA	2300 to 2400	900	28	30	18.7	33	-	-40 ^[2]

[1] Single carrier IS-95 with pilot, paging, sync and 6 traffic channels (Walsh codes 8 - 13). PAR = 9.7 dB at 0.01 % probability on the CCDF. Channel bandwidth is 1.2288 MHz.

[2] 3GPP; test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF. Channel bandwidth is 3.84 MHz.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Designed for low memory effects providing excellent digital pre-distortion capability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

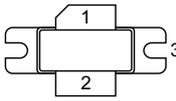
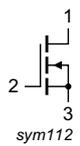
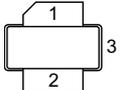
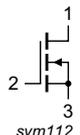
1.3 Applications

- RF power amplifiers for industrial and multi carrier applications in the 2300 MHz to 2400 MHz frequency range



2. Pinning information

Table 2. Pinning

Pin	Description	Simplified outline	Graphic symbol
BLF2425M7L100 (SOT502A)			
1	drain		 sym112
2	gate		
3	source [1]		
BLF2425M7LS100 (SOT502B)			
1	drain		 sym112
2	gate		
3	source [1]		

[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BLF2425M7L100	-	flanged ceramic package; 2 mounting holes; 2 leads	SOT502A
BLF2425M7LS100	-	earless flanged ceramic package; 2 leads	SOT502B

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
T_{stg}	storage temperature		-65	+150	°C
T_j	junction temperature		-	200	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Typ	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	$T_{case} = 80\text{ °C}; P_L = 100\text{ W}$	0.3	K/W

6. Characteristics

Table 6. DC characteristics

$T_j = 25\text{ °C}$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0\text{ V}; I_D = 1\text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10\text{ V}; I_D = 150\text{ mA}$	1.5	1.8	2.3	V
I_{DSS}	drain leakage current	$V_{GS} = 0\text{ V}; V_{DS} = 28\text{ V}$	-	-	5	μA
I_{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75\text{ V}; V_{DS} = 10\text{ V}$	25.1	29	-	A
I_{GSS}	gate leakage current	$V_{GS} = 11\text{ V}; V_{DS} = 0\text{ V}$	-	-	500	nA
g_{fs}	forward transconductance	$V_{DS} = 10\text{ V}; I_D = 5.35\text{ A}$	-	10.5	-	S
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75\text{ V}; I_D = 5.25\text{ A}$	-	0.1	-	Ω

Table 7. RF characteristics

Test signal: single carrier IS-95 with pilot, paging, sync and 6 traffic channels (Walsh codes 8 - 13). PAR = 9.7 dB at 0.01 % probability on the CCDF, channel bandwidth is 1.2288 MHz; $f_1 = 2300\text{ MHz}$; $f_2 = 2400\text{ MHz}$; RF performance at $V_{DS} = 28\text{ V}$; $I_{Dq} = 900\text{ mA}$; $T_{case} = 25\text{ °C}$; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
G_p	power gain	$P_{L(AV)} = 20\text{ W}$	17.3	18	-	dB
RL_{in}	input return loss	$P_{L(AV)} = 20\text{ W}$	-	-14	-	dB
η_D	drain efficiency	$P_{L(AV)} = 20\text{ W}$	22	27	-	%
$ACPR_{885k}$	adjacent channel power ratio (885 kHz)	$P_{L(AV)} = 20\text{ W}$	-	-46	-40	dBc

7. Test information

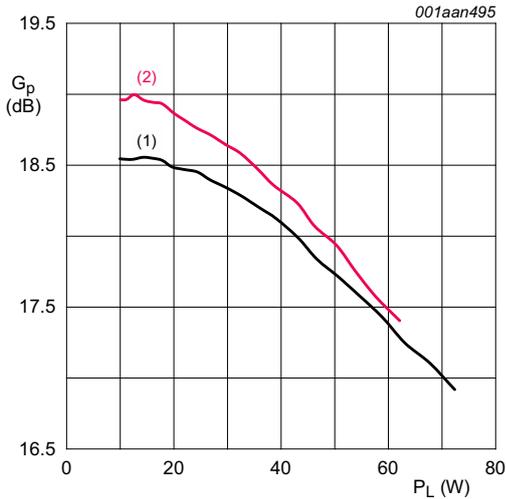
7.1 Ruggedness in class-AB operation

The BLF2425M7L100 and BLF2425M7LS100 are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: $V_{DS} = 28\text{ V}$; $I_{Dq} = 900\text{ mA}$; $P_L = 100\text{ W}$ (CW); $f = 2300\text{ MHz}$.

7.2 Graphical data

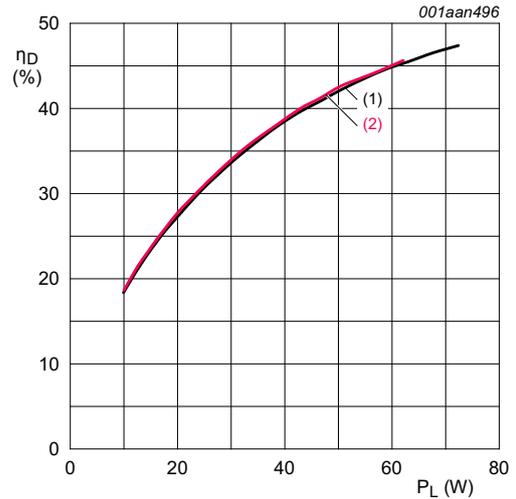
7.2.1 Single carrier IS-95

Single carrier IS-95 with pilot, paging, sync and 6 traffic channels (Walsh codes 8 - 13).
 PAR = 9.7 dB at 0.01 % probability on the CCDF. Channel bandwidth is 1.2288 MHz.



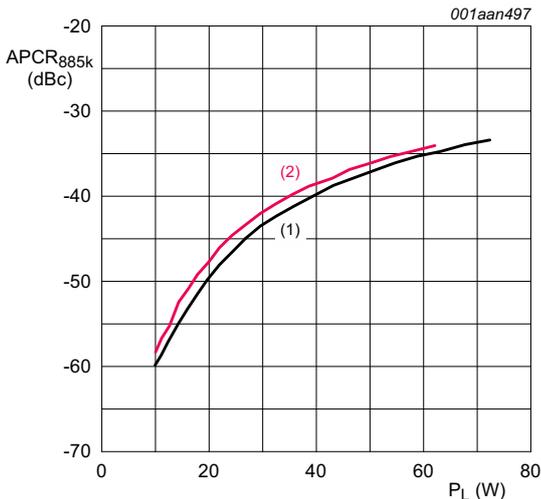
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 1. Power gain as a function of output power; typical values



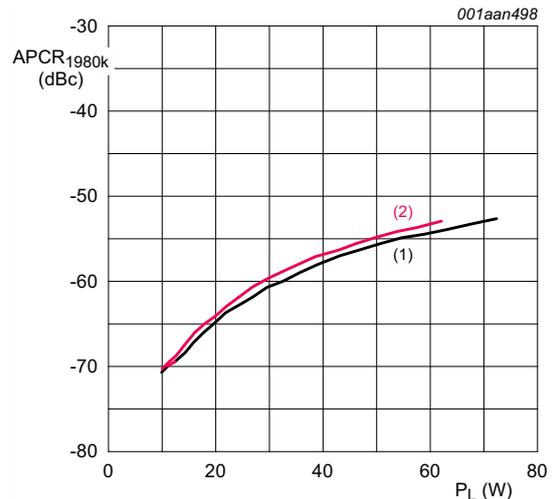
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 2. Drain efficiency as a function of output power; typical values



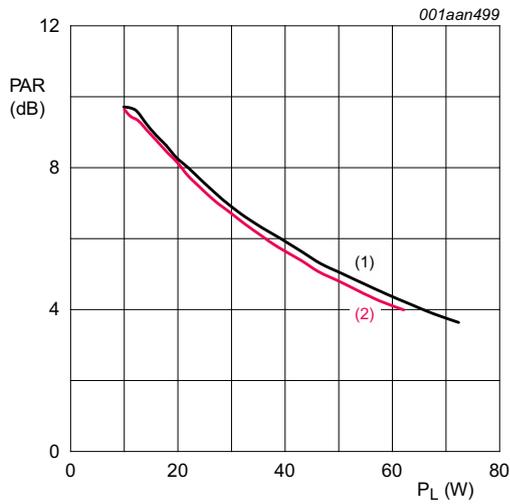
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 3. Adjacent channel power ratio (885 kHz) as a function of output power; typical values



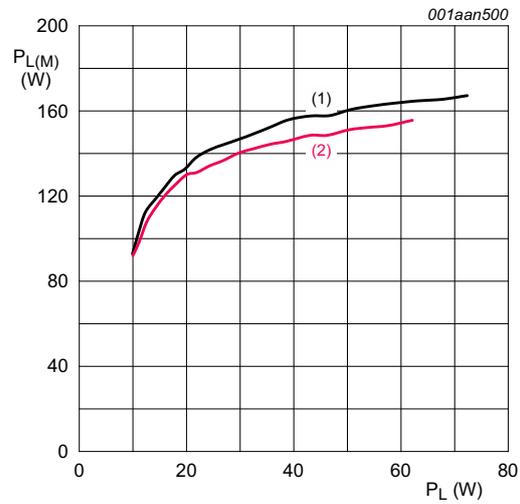
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 4. Adjacent channel power ratio (1980 kHz) as a function of output power; typical values



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}$.
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

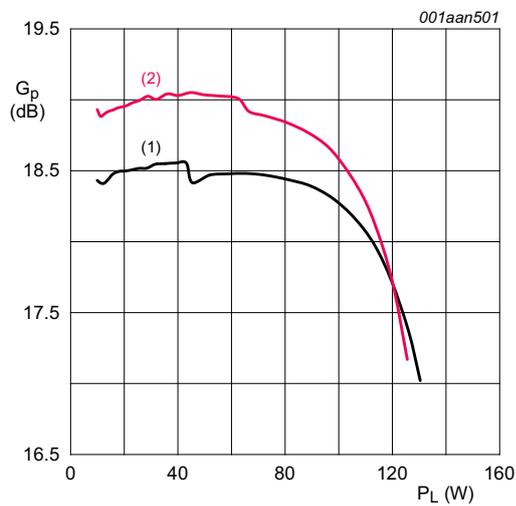
Fig 5. Peak-to-average power ratio as a function of output power; typical values



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}$.
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

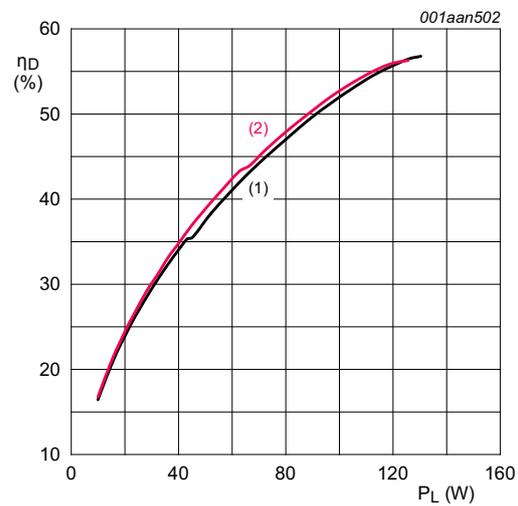
Fig 6. Peak power as a function of output power; typical values

7.2.2 Pulsed CW



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}$.
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 7. Power gain as a function of output power; typical values

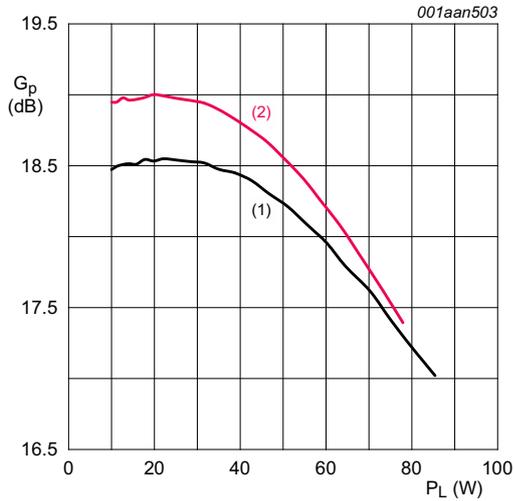


$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}$.
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 8. Drain efficiency as a function of output power; typical values

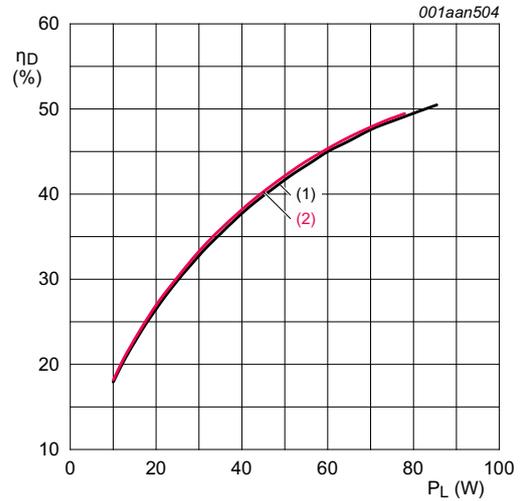
7.2.3 Single carrier W-CDMA

3GPP; test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF. Channel bandwidth is 3.84 MHz.



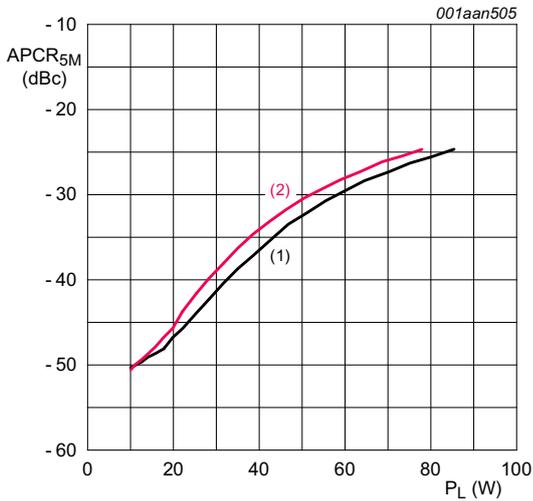
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 9. Power gain as a function of output power; typical values



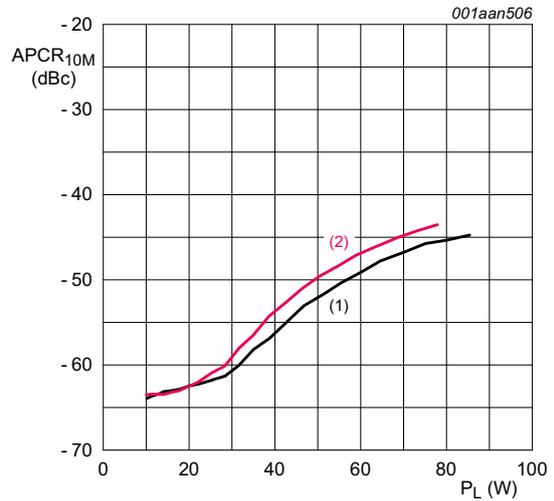
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 10. Drain efficiency as a function of output power; typical values



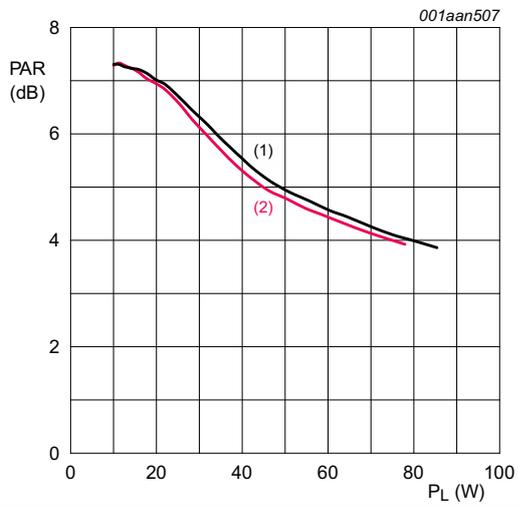
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 11. Adjacent channel power ratio (5 MHz) as a function of output power; typical values



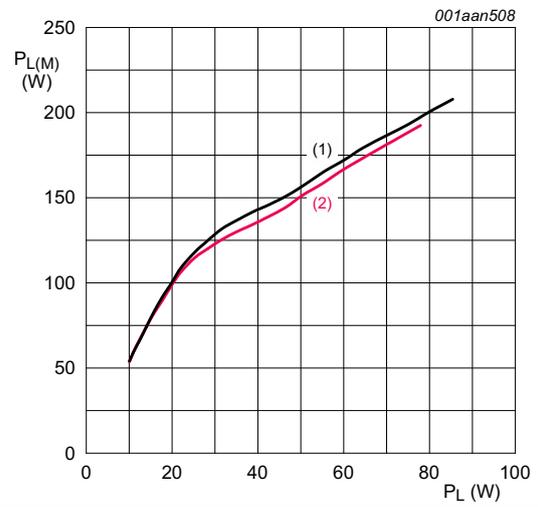
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 12. Adjacent channel power ratio (10 MHz) as a function of output power; typical values



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 13. Peak-to-average power ratio as a function of output power; typical values



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2300\text{ MHz}$
 (2) $f = 2400\text{ MHz}$

Fig 14. Peak output power as a function of output power; typical values

8. Package outline

Flanged ceramic package; 2 mounting holes; 2 leads

SOT502A

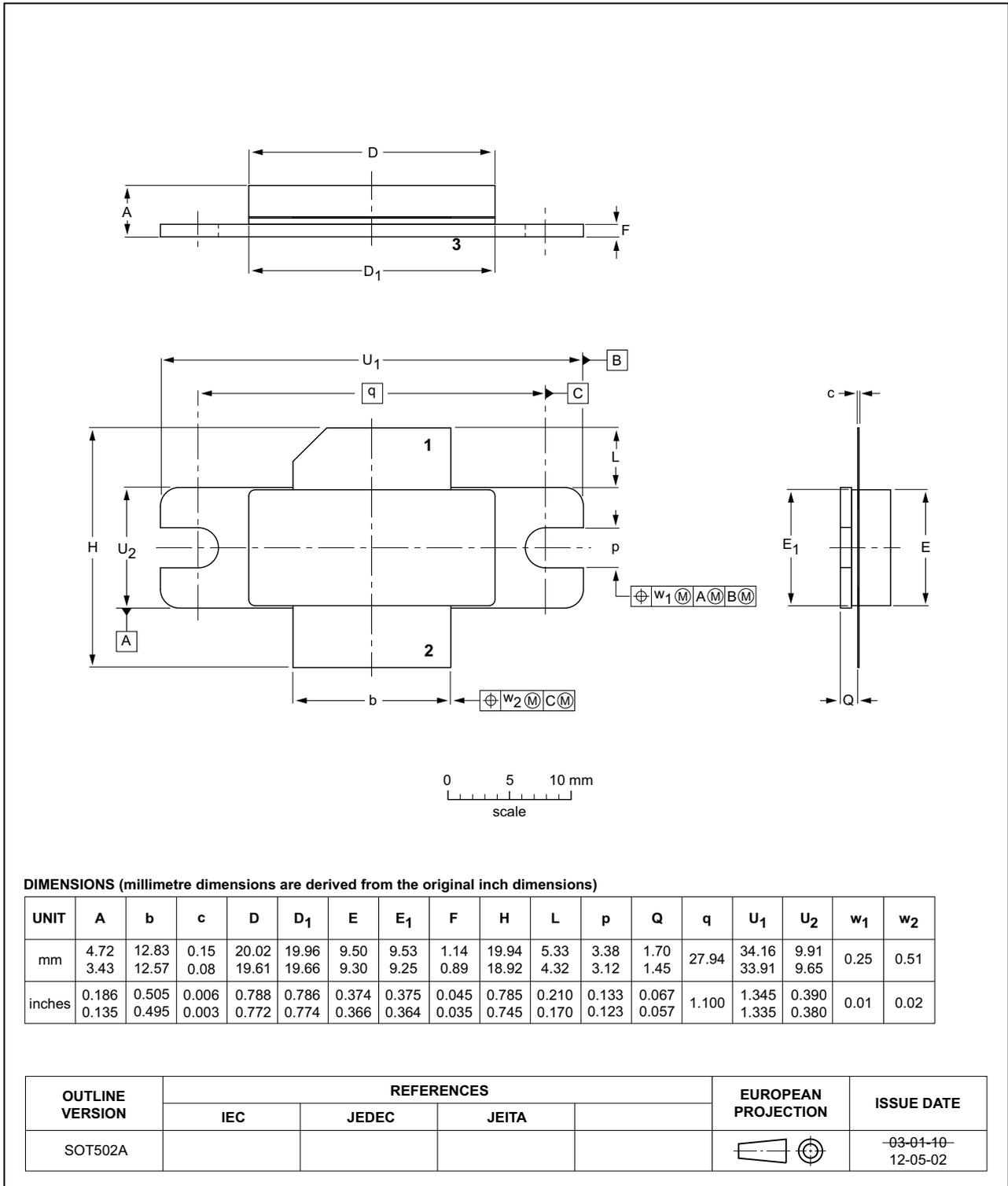


Fig 15. Package outline SOT502A

Earless flanged ceramic package; 2 leads

SOT502B

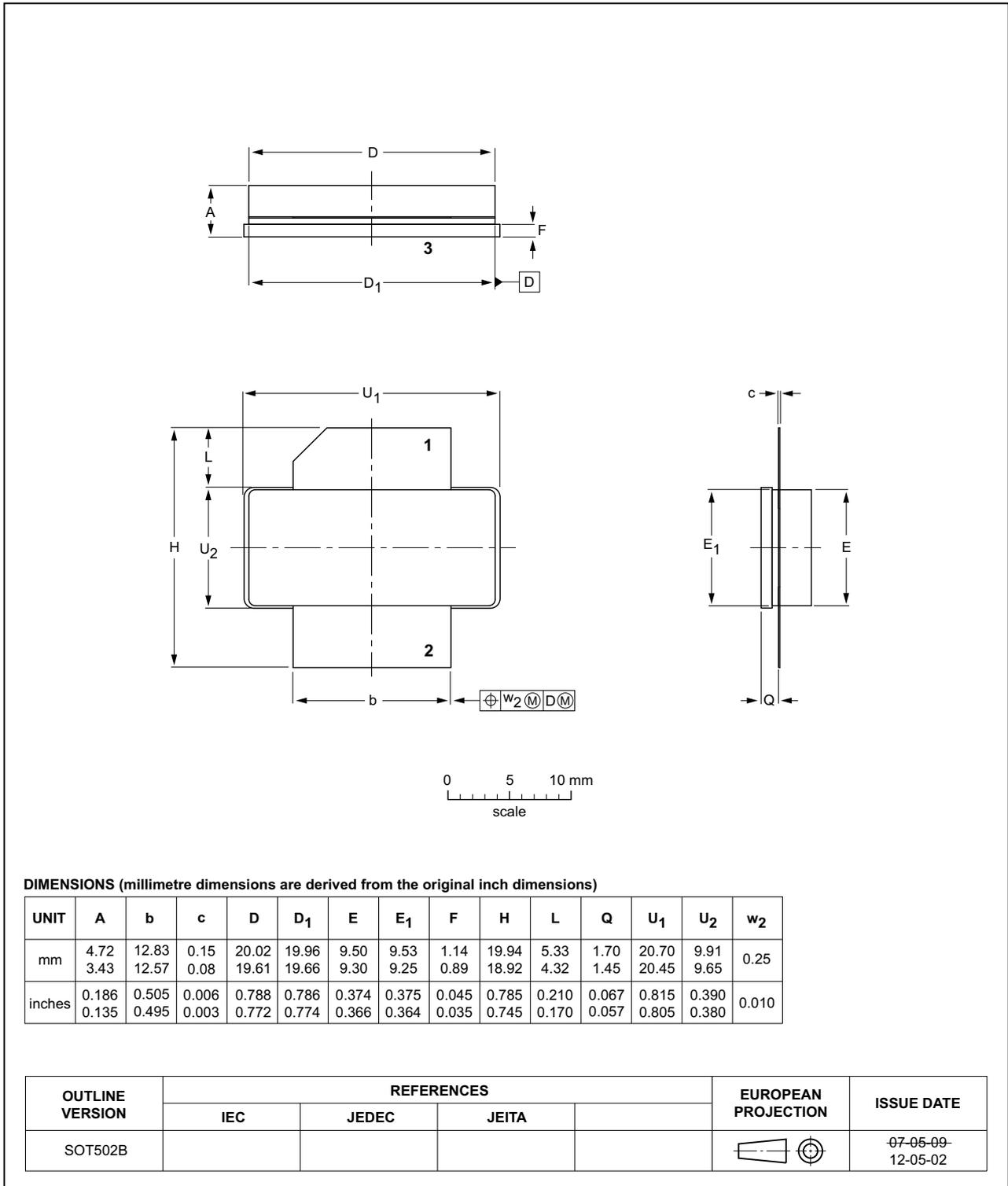


Fig 16. Package outline SOT502B

9. Abbreviations

Table 8. Abbreviations

Acronym	Description
3GPP	3rd Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
IS-95	Interim Standard 95
LDMOS	Laterally Diffused Metal Oxide Semiconductor
PAR	Peak-to-Average Ratio
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

10. Revision history

Table 9. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF2425M7L100_2425M7LS100 v.1	20131206	Product data sheet	-	-

11. Legal information

11.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

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